

A LOW-COST, RECONFIGURABLE THIN- FILM INSPECTION SYSTEM

TOWARDS LARGE AREA THIN-FILM REFLECTOMETRY

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OVERVIEW

- Motivation
 - Challenges
- State of the Art
- Approach
- Status
- Future work

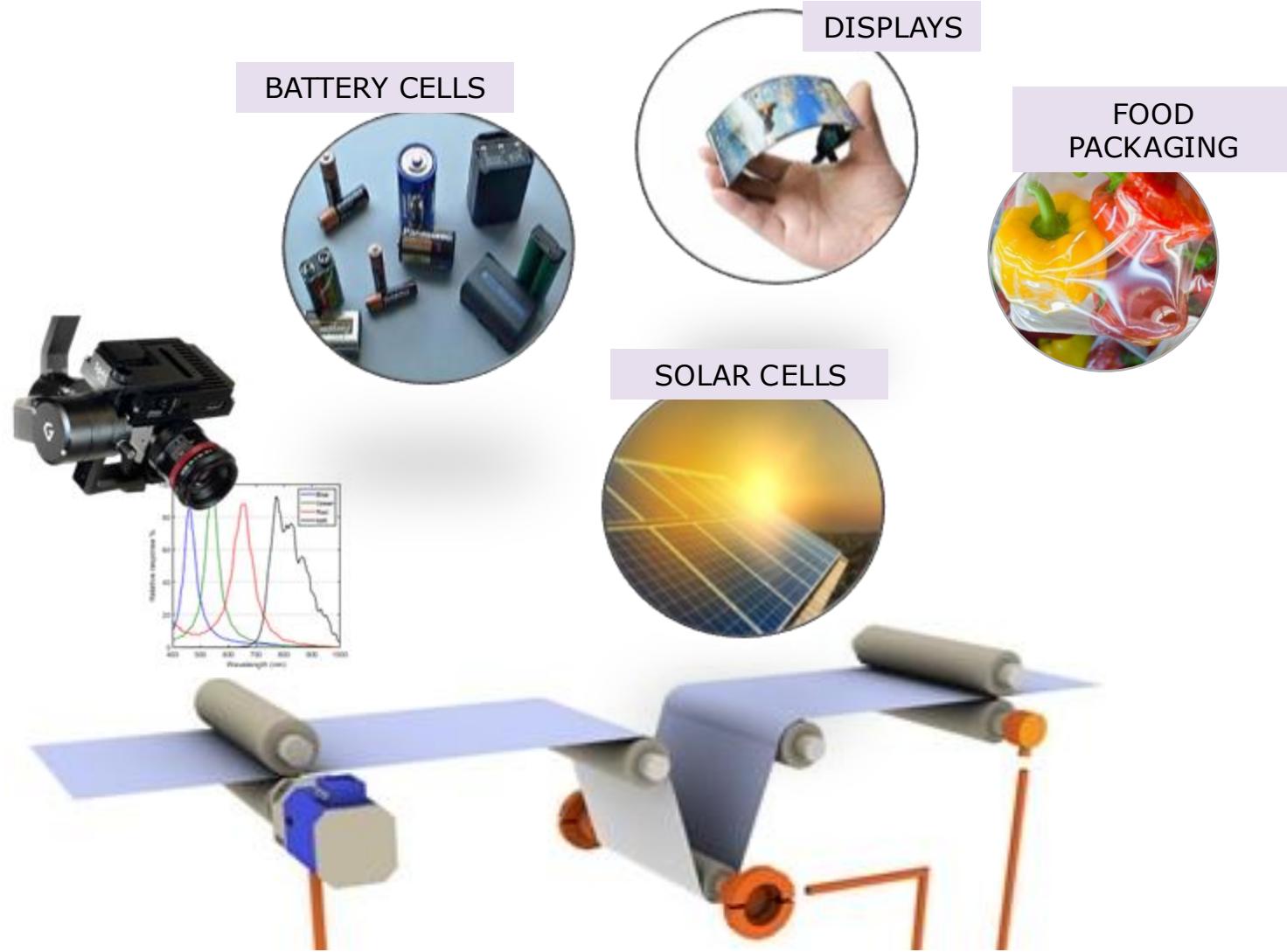


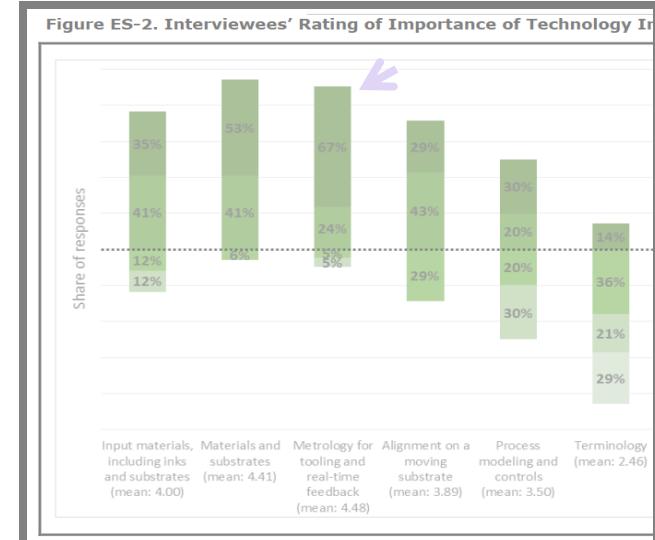
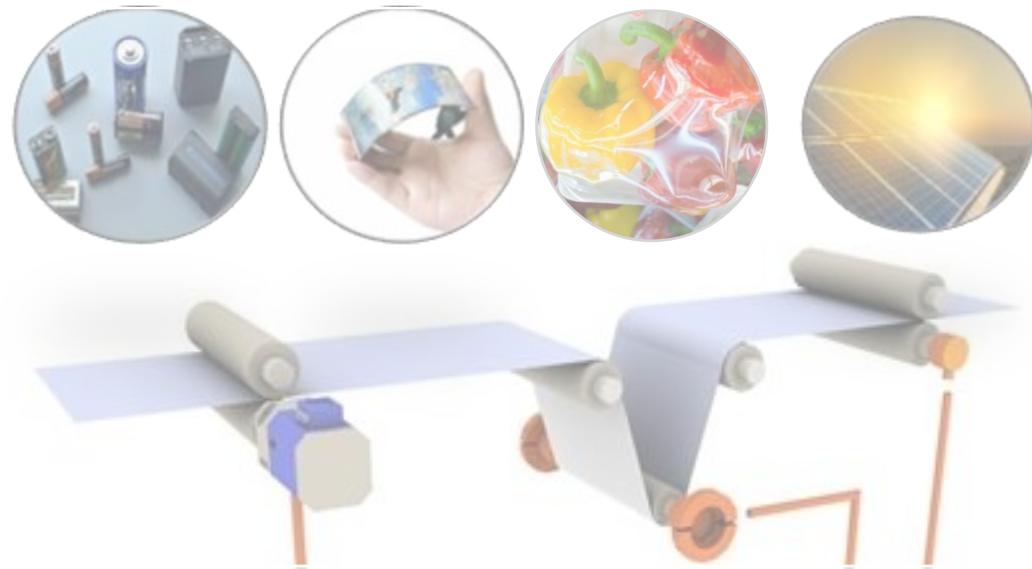
ILLUSTRATION OF INDUSTRIAL THIN-FILM INSPECTION

MOTIVATION

- “Metrology has not kept up with thin-film manufacturing speeds” (Maize et al, 2022; NIST 2016)
- Large-area thin films are everywhere!
 - used in PV, displays, batteries, and packaging
- Industry often needs 100% inline, real-time inspection

CHALLENGES

- Metrology is too computationally heavy or too slow
- Also, too expensive



IMPORTANCE OF METROLOGY IN R2R MANUFACTURING

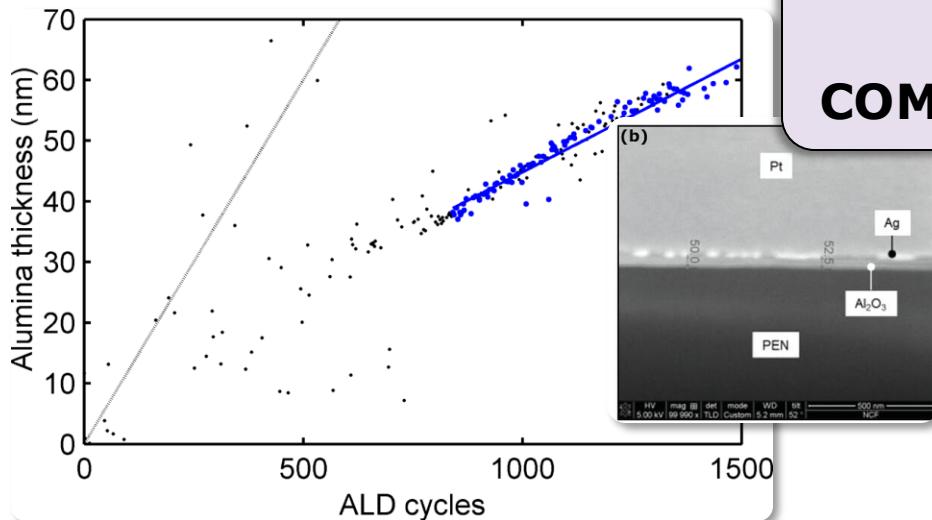
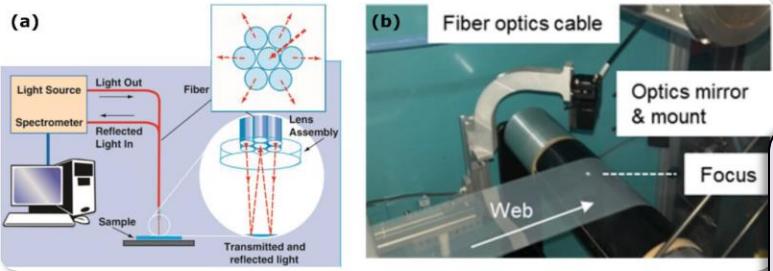


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STATE OF THE ART

POINT THIN FILM INSPECTION

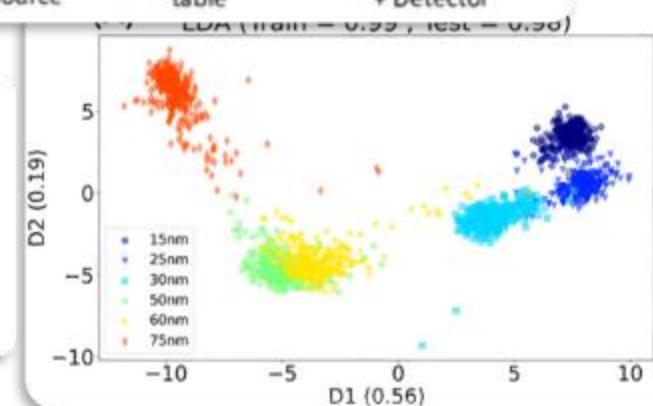
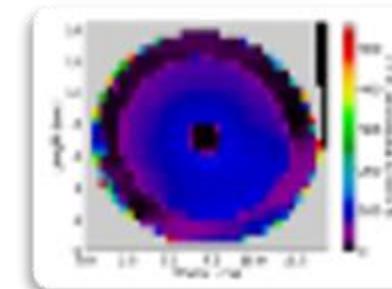
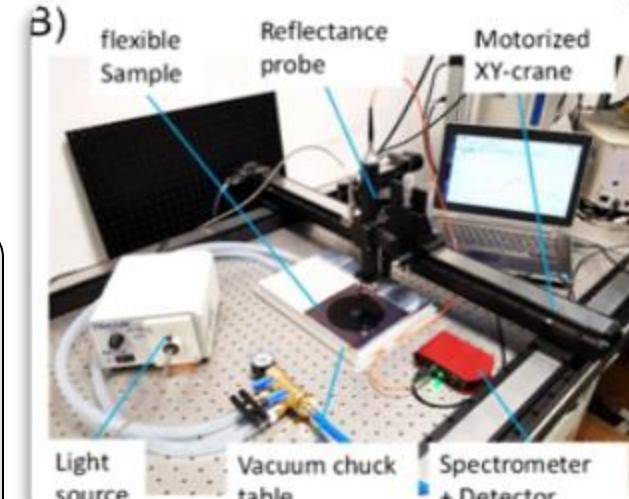


FOR 52NM ALD MOVING AT 1M/S Al₂O₃ (2014)

ALL USE FULL
REFLECTANCE SPECTRA,

WHICH CAN BE
COMPUTATIONALLY HEAVY

AREA MAPPING

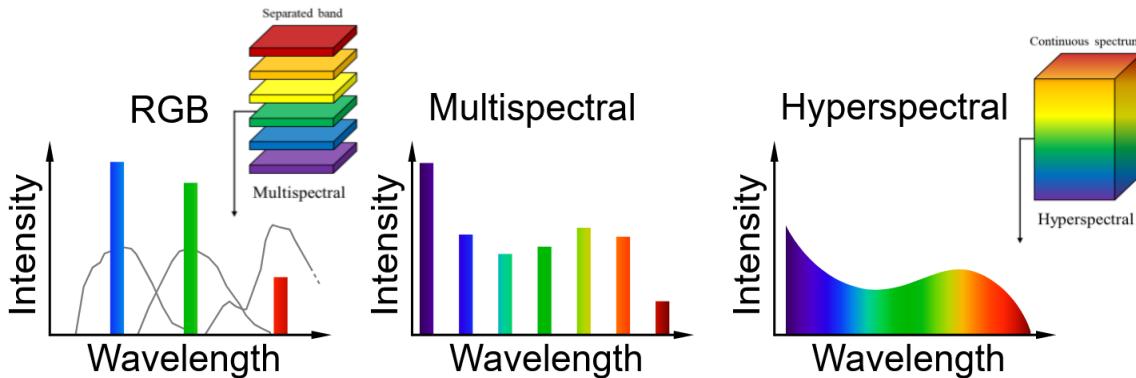


25NM AL_xO FILM ON SILICON, (ENRIC, 2021)

BACKGROUND

Reflectance spectra can be used to estimate film uniformity.

- Multispectral and RGB Cameras have **less spectral resolution**
- Each pixel creates has



REDUCED SPECTRAL RESOLUTION WITH HYPERSPECTRAL

APPROACH

- Use multispectral/RGB cameras instead
 - Less computationally heavy and
 - Less expensive

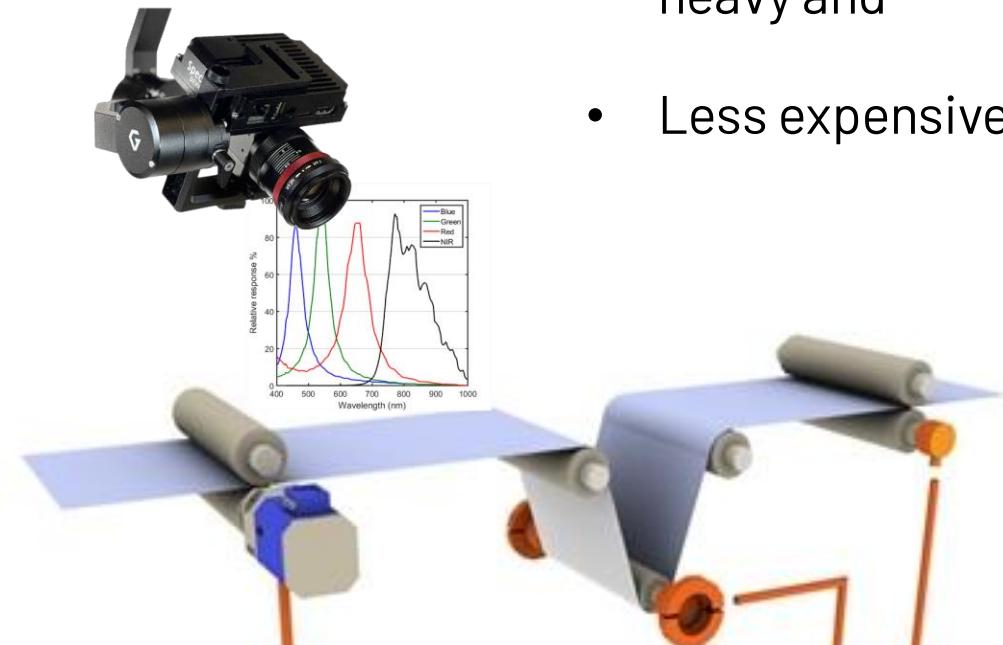
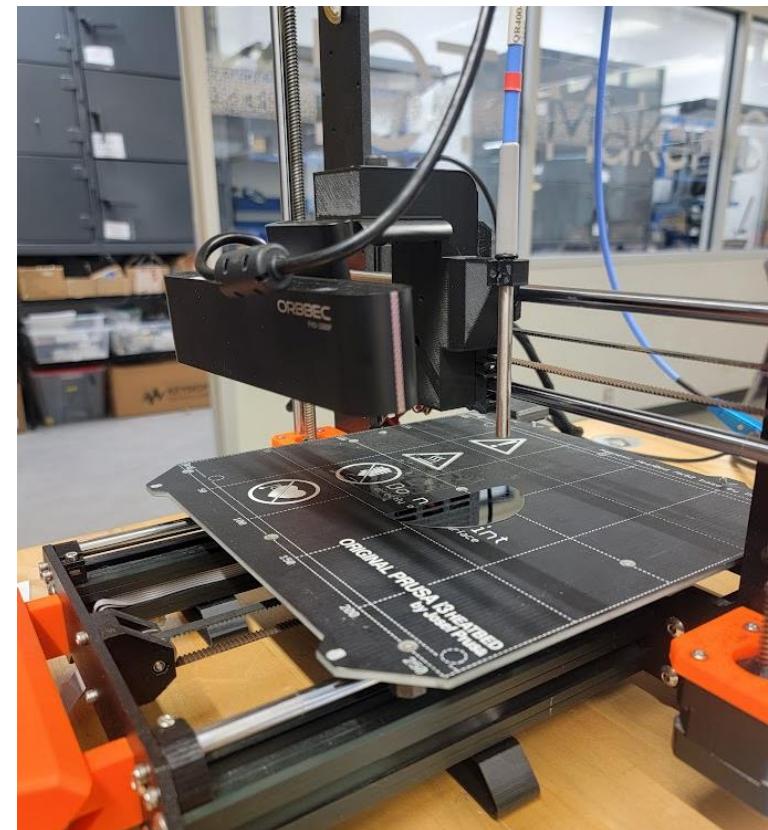
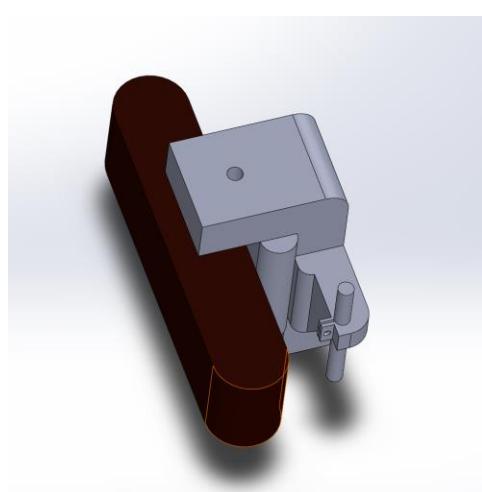
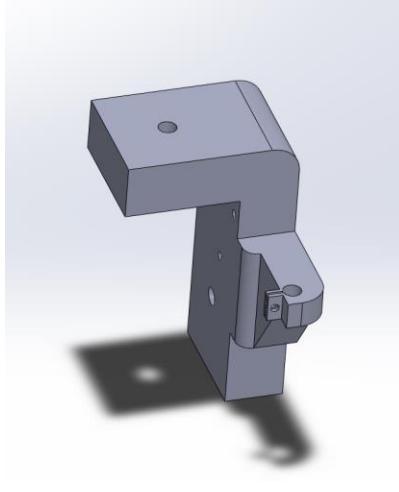


ILLUSTRATION OF INDUSTRIAL THIN-FILM INSPECTION



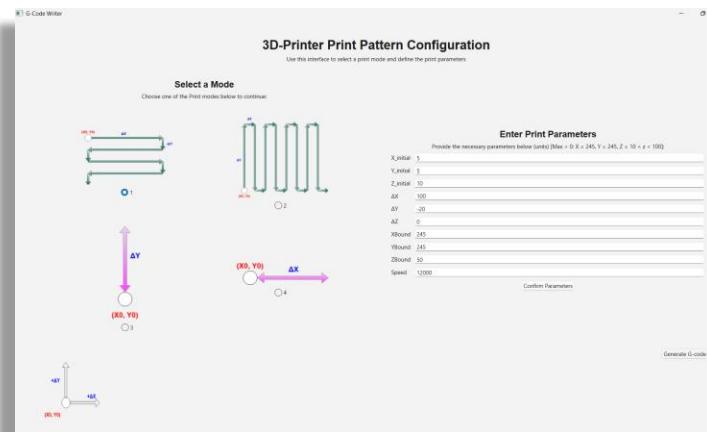
WORK SO FAR - GANTRY DESIGN

- Prusa 3D MK3s was adapted to create an operational gantry
- A rig was designed and built to attach camera and spectrometer to the gantry

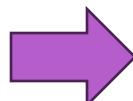


WORK SO FAR - USER INTERFACE

- A user interface was built to turn user instruction into machine procedure

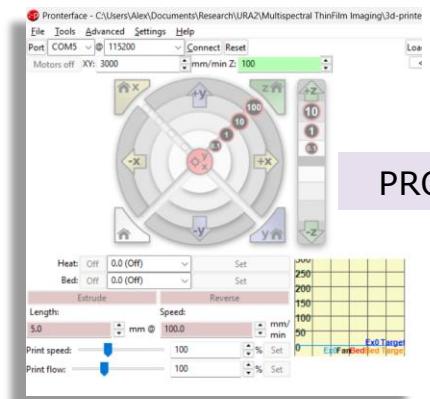


USER INTERFACE

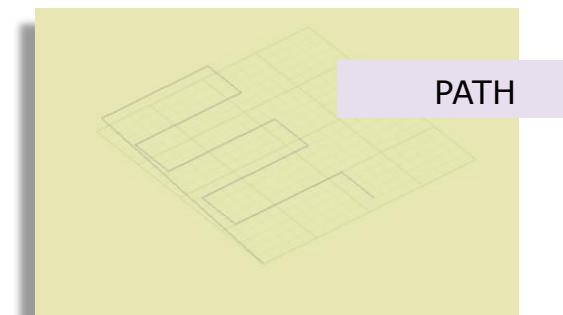


```
G21  
G90  
G1 X5 Y200 Z10 F12000  
G1 X105 F12000  
G1 Y100 F12000  
G1 X5 F12000  
G1 Y120 F12000  
G1 X105 F12000  
G1 Y80 F12000  
G1 X5 F12000  
G1 Y40 F12000  
G1 X105 F12000  
G1 Y0 F12000
```

G-CODE

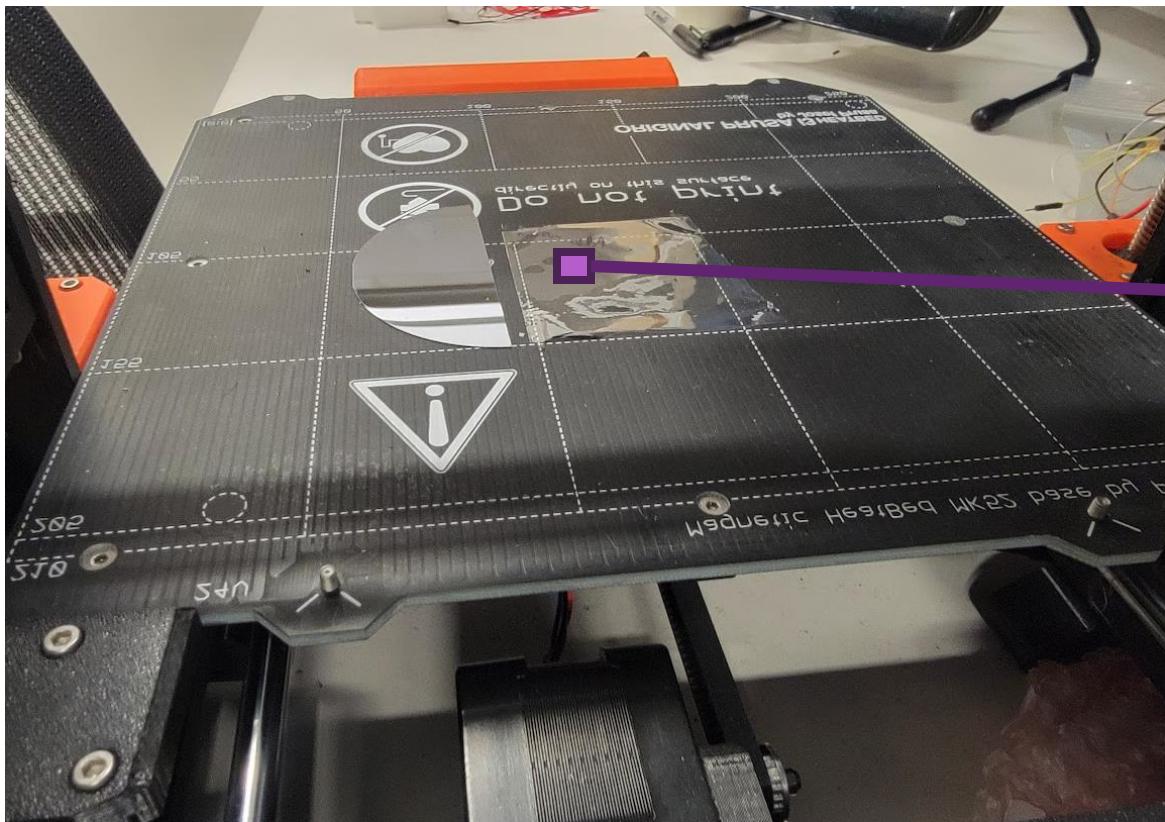


PRONTERFACE



PATH

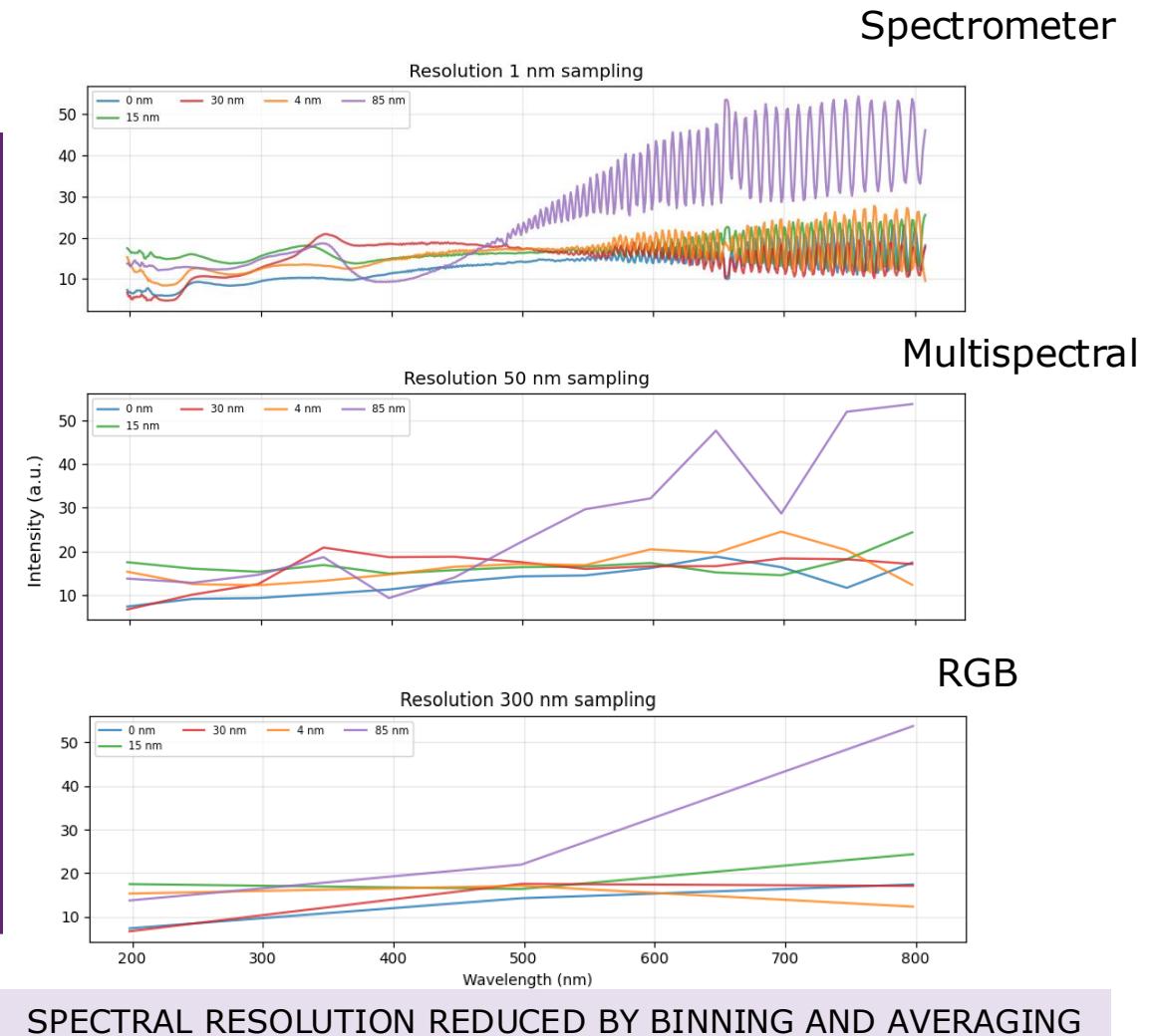
PRELIMINARY DATA



IMAGES OF SAMPLE ON STAGE

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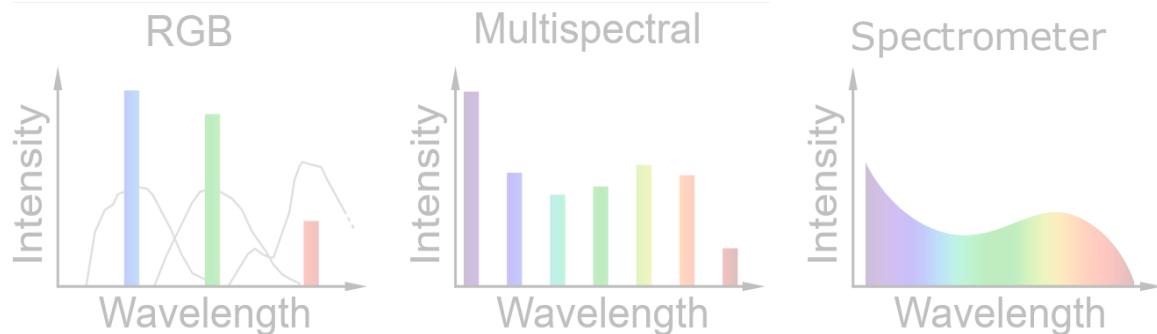


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FUTURE WORK

- Improve UI and Camera rig
- Test on more samples (from partners)
- Increase metrology accuracy
- Integrate into real system



REDUCED SPECTRAL RESOLUTION WITH HYPERSPECTRAL

THANK YOU!



ILLUSTRATION OF INDUSTRIAL THIN-FILM INSPECTION



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Thank you! Questions?